

## **AMENDMENTS TO THE CLAIMS**

The following listing of claims will replace all prior versions and listings of claims in the application.

### **LISTING OF CLAIMS**

1. (withdrawn) A conductor-pattern testing method for inspecting an electrode substrate having a conductor pattern constituted by a plurality of elongated conductors formed in parallel to each other on a base and further having a dummy pattern constituted by a plurality of dummy conductors formed in an area on said base where said conductor pattern is not formed, said method examining electrical characteristics among said plurality of conductors by establishing the contact of at least two probes having a positional relationship defined so that the two probes are brought into contact with at least two conductors among said plurality of conductors,

wherein said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern are formed in segments so as to prevent two or more of the probes from being simultaneously in contact with any one of said plurality of dummy conductors and said at least two probes are progressively moved for inspection in the array direction of said plurality of conductors.

2. (withdrawn) A conductor-pattern testing method according to Claim 1, wherein said plurality of conductors are electrodes or wiring lines formed on said base.

3. (withdrawn) A conductor-pattern testing method according to Claim 1, wherein said dummy conductors disposed in the array direction of said plurality of electrodes to constitute said dummy pattern are mutually set apart between any pair of said at least two probes in the extending direction of said plurality of electrodes.

4. (withdrawn) A conductor-pattern testing method according to Claim 1, wherein each of said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern is shorter when viewed along the extending direction of said plurality of conductors than the minimum length between any pair of said at least two probes in the extending direction of said plurality of conductors.

5. (withdrawn) A conductor-pattern testing method according to Claim 1, wherein said plurality of dummy conductors disposed in the array direction of said plurality of conductors to constitute said dummy pattern are mutually separated in the array direction of said plurality of conductors.

6. (withdrawn) A conductor-pattern testing method according to Claim 1, wherein said base is a substrate, and said electrode substrate is an electro-optical device in which a plurality of electrodes and wiring lines are formed in a particular pattern on the surface of said substrate and electro-optical material to be affected by an electric field generated by said plurality of electrodes are further disposed thereover.

7. (currently amended) An electrooptical device having a conductor pattern constituted by a plurality of elongated conductors formed in parallel to each other on a base, further having a dummy pattern constituted by a plurality of dummy conductors formed in an area on said base where said conductor pattern is not formed, the dummy patterns including a plurality of dummy pattern rows aligned parallel to each other and to the elongated conductors, and in which electrooptical material is disposed on said conductor pattern, wherein said plurality of dummy conductors disposed in ~~the~~ an array direction of said plurality of conductors to constitute said dummy pattern are mutually separated by gaps in an extending direction of said plurality of elongated conductors, the gaps in adjacent dummy pattern rows being shifted out of alignment from each other with respect to the extending direction.

8. (currently amended) An electro-optical device comprising:

a conductor pattern having a plurality of elongated conductors formed in parallel to each other in a first area on a base;

said conductor pattern having a dummy pattern, said dummy pattern being a plurality of dummy conductors formed in at least a second area on said base, said dummy conductors being arranged in rows of dummy conductors, each row being parallel to an adjacent row and to said elongated conductors, said rows being separated by a gap, the gaps in adjacent dummy pattern rows being shifted out of alignment from each other with respect to an extending direction of said elongated conductors; and

electro-optical material being disposed on said conductor pattern;

wherein each of said plurality of dummy conductors are disposed in an array direction of said plurality of elongated conductors to form said dummy pattern, and each of said plurality of dummy conductors are mutually electrically separated in the array direction of said plurality of elongated conductors.

9. (currently amended) The electro-optical device according to Claim 8, wherein at least two of said plurality of dummy conductors disposed in the array direction of said plurality of elongated conductors are each mutually electrically separated in ~~an~~ the extending direction of said plurality of elongated conductors.

10. (previously presented) The electro-optical device according to Claim 8, wherein each of said plurality of dummy conductors being mutually electrically separated in the array direction of said plurality of elongated conductors have a dummy conductor width and a dummy conductor spacing equivalent to a width and a spacing of each of the elongated conductors.

11. (previously presented) The electro-optical device according to Claim 10, wherein said plurality of elongated conductors formed in parallel to each other have a fixed pitch.

12. (previously presented) The electro-optical device according to Claim 11, wherein said plurality of dummy conductors being mutually electrically separated in the array direction of said plurality of elongated conductors have a dummy conductor pitch equal to the fixed pitch of the plurality of elongated conductors.

13. (previously presented) The electro-optical device according to Claim 8, wherein said plurality of elongated conductors and said plurality of dummy conductors are selected from the group consisting of electrodes and wiring lines formed on said base.

14. (previously presented) An electro-optical device comprising:

- a conductor pattern having an electro-optical material disposed thereon;
- said conductor pattern having a plurality of conductors, said plurality of conductors formed as adjacent pairs of conductors on a first area of a base;
- said conductor pattern having a plurality of dummy conductors, said plurality of dummy conductors formed as adjacent pairs of dummy conductors on at least a second area of said base;
- each of said plurality of conductors and each of said plurality of dummy conductors having a common width;
- each of said adjacent pairs of conductors having a common pitch; said common pitch matching a probe pair spacing; and
- each of said plurality of dummy conductors being disposed in an array direction of said plurality of conductors;
- wherein each of the adjacent pairs of dummy conductors have a dummy conductor pitch matching the probe pair spacing such that the probe pair spacing is retained in the array direction of said plurality of dummy conductors.

15. (previously presented) The electro-optical device according to Claim 14, wherein at least two of said dummy conductors have a length in an extending direction of said plurality of conductors.

16. (previously presented) The electro-optical device according to Claim 15, wherein the at least two of said plurality of dummy conductors are separated by a gap, said gap perpendicular to the length in the extending direction of said plurality of conductors.

17. (previously presented) The electro-optical device according to Claim 16, wherein said gap comprises a gap dimension smaller than a dimension of the probe pair spacing.